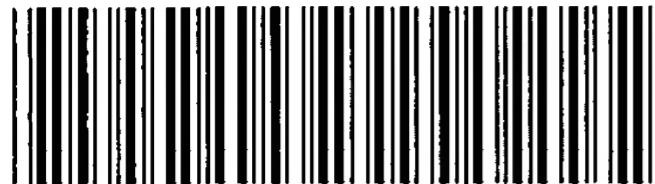


<b>Search Notes</b>  	<b>Application/Control No.</b>  10618829	<b>Applicant(s)/Patent Under Reexamination</b>  MEYER ET AL.
	<b>Examiner</b>  Kiss, Eric B.	<b>Art Unit</b>  2192

SEARCHED			
Class	Subclass	Date	Examiner
717	114, 117, 135, 140, 174	12/07/2007	EBK
719	328	12/07/2007	EBK
714	28, 30, 31	12/07/2007	EBK

SEARCH NOTES		
Search Notes	Date	Examiner
Plus Search	10/30/2006	JJR
East (see attached search notes)	10/30/2006	JJR
Palm Inventor Search	10/30/2006	JJR
Google (test bench co-simulation)	1/02/2006	JJR
IEEE (see attached search notes)	1/5/2006	JJR
ACM/PORTAL (see attached search notes)	1/05/2006	JJR
updated EAST search (see search history printout)	12/07/2007	EBK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	Interference searched (US-PGPUB; text search--see search history printout)	12/07/2007	EBK